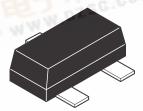


# ZXMP2120FF 200V SOT23F P-channel enhancement mode MOSFET

#### Summary

| V <sub>(BR)DSS</sub> | $R_{DS(on)}$ ( $\Omega$ )   | I <sub>D</sub> (mA) |  |
|----------------------|-----------------------------|---------------------|--|
| -200                 | 28 @ V <sub>GS</sub> = -10V | -137                |  |



#### **Description**

This 200V enhancement mode P-channel MOSFET provides users with a competitive specification offering efficient power handling capability, high impedance and freedom from thermal runaway and thermally induced secondary breakdown.

Applications benefiting from this device include a variety of telecom and general high voltage circuits.

#### **Features**

- High voltage
- Low on-resistance
- Fast switching speed
- Low gate drive
- · Low threshold
- SOT23 FLAT package

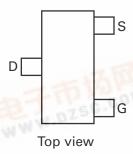
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#### **Applications**

Active clamping of primary side MOSFETs in 48 volt DC-DC converters

#### **Ordering information**

| Device       | Reel size<br>(inches) | Tape width<br>(mm) | Quantity per reel |
|--------------|-----------------------|--------------------|-------------------|
| ZXMP2120FFTA | 7                     | 8                  | 3,000             |



#### **Device marking**

1C4

#### **Absolute maximum ratings**

| Parameter   | Symbol                            | Limit       | Unit  |
|---|-----------------------------------|-------------|-------|
| Drain-source voltage  | V <sub>DSS</sub>                  | -200        | V     |
| Gate-source voltage   | V <sub>GS</sub>                   | ± 20        | V     |
| Continuous drain current @ V <sub>GS</sub> = 10V; T <sub>amb</sub> =25°C <sup>(a)</sup> | I <sub>D</sub>                    | -137        | mA    |
| Pulsed drain current <sup>(c)</sup>   | I <sub>DM</sub>                   | -0.8        | Α     |
| Pulsed source current (body diode)(c)   | I <sub>SM</sub>                   | -0.8        | Α     |
| Power dissipation at T <sub>amb</sub> =25°C <sup>(a)</sup>                              | P <sub>D</sub>                    | 1           | W     |
| Linear derating factor  |                                   | 8           | mW/°C |
| Power dissapation at T <sub>amb</sub> =25°C <sup>(b)</sup>                              | $P_{D}$                           | 1.5         | W     |
| Linear derating factor  |                                   | 12.3        | mW/°C |
| Operating and storage temperature range   | T <sub>j</sub> , T <sub>stg</sub> | -55 to +150 | °C    |

#### Thermal resistance

| Parameter                          | Symbol          | Limit | Unit |
|------------------------------------|-----------------|-------|------|
| Junction to ambient <sup>(a)</sup> | $R_{\Theta JA}$ | 125   | °C/W |
| Junction to ambient <sup>(b)</sup> | $R_{\Theta JA}$ | 81    | °C/W |

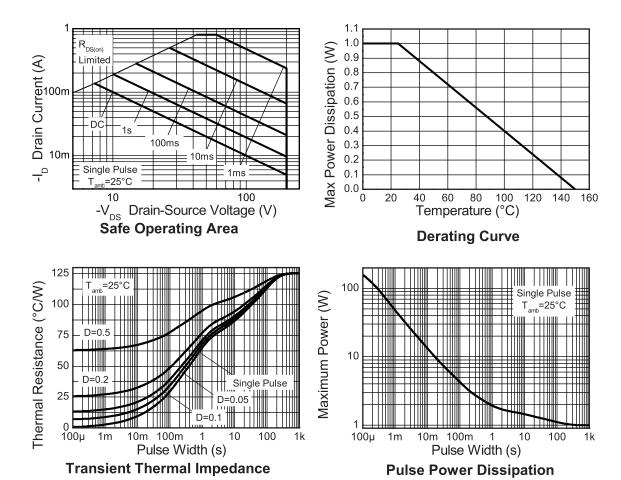
#### NOTES:

<sup>(</sup>a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions

<sup>(</sup>b) For a device surface mounted on FR4 pcb measured at t  $\leq\!5$  sec.

<sup>(</sup>c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width  $300\mu s$  - pulse width limited by maximum junction temperature.

#### Thermal characteristics



# Electrical characteristics (at T<sub>amb</sub> = 25°C unless otherwise stated)

| Parameter                                   | Symbol               | Min. | Max. | Unit | Conditions   |  |  |  |
|---|----------------------|------|------|------|--|--|--|--|
| Static                                      |                      |      |      |      |  |  |  |  |
| Drain-source breakdown voltage              | V <sub>(BR)DSS</sub> | -200 |      | V    | I <sub>D</sub> = 1mA, V <sub>GS</sub> =0V                |  |  |  |
| Zero gate voltage drain current             | I <sub>DSS</sub>     |      | -10  | μΑ   | V <sub>DS</sub> = -200V, V <sub>GS</sub> =0V             |  |  |  |
|   |                      |      | -100 | μΑ   | $V_{DS}$ = -160V, $V_{GS}$ =0V, T=125C <sup>(‡)</sup>    |  |  |  |
| Gate-body leakage                           | I <sub>GSS</sub>     |      | 20   | nA   | V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V               |  |  |  |
| Gate-source threshold voltage               | V <sub>GS(th)</sub>  | -1.5 | -3.5 | V    | I <sub>D</sub> = 250μA, V <sub>DS</sub> =V <sub>GS</sub> |  |  |  |
| Static drain-source on-state resistance (*) | R <sub>DS(on)</sub>  |      | 28   | Ω    | V <sub>GS</sub> = -10V, I <sub>D</sub> = -150mA          |  |  |  |
| On-state drain current <sup>(*)</sup>       | I <sub>D(on)</sub>   | -300 |      | mA   | V <sub>DS</sub> = -25V, V <sub>GS</sub> =-10V            |  |  |  |
| Forward transconductance(*) (‡)             | 9 <sub>fs</sub>      | 50   |      | mS   | V <sub>DS</sub> = -25V, I <sub>D</sub> = -150mA          |  |  |  |
| Dynamic <sup>(‡)</sup>                      |                      |      |      |      |  |  |  |  |
| Input capacitance                           | C <sub>iss</sub>     |      | 100  | pF   | V <sub>DS</sub> = -25V, V <sub>GS</sub> =0V              |  |  |  |
| Output capacitance                          | C <sub>oss</sub>     |      | 25   | pF   | f=1MHz   |  |  |  |
| Reverse transfer capacitance                | C <sub>rss</sub>     |      | 7    | pF   |  |  |  |  |
| Switching (†) (‡)                           | Switching (†) (‡)    |      |      |      |  |  |  |  |
| Turn-on-delay time                          | t <sub>d(on)</sub>   |      | 7    | ns   | V <sub>DD</sub> = -25V, V <sub>GS</sub> = -10V           |  |  |  |
| Rise time                                   | t <sub>r</sub>       |      | 15   | ns   | I <sub>D</sub> = -150mA                                  |  |  |  |
| Turn-off delay time                         | t <sub>d(off)</sub>  |      | 12   | ns   | R <sub>SOURCE</sub> ≈ 50Ω                                |  |  |  |
| Fall time                                   | t <sub>f</sub>       |      | 15   | ns   |  |  |  |  |

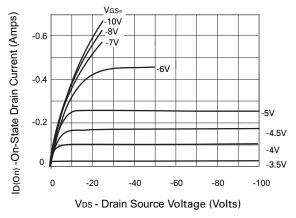
#### NOTES:

<sup>(\*)</sup> Measured under pulsed conditions. Pulse width  ${\leq}300\mu s;$  duty cycle  ${\leq}2\%.$ 

<sup>(†)</sup> Switching characteristics are independent of operating junction temperature.

<sup>(‡)</sup> For design aid only, not subject to production testing.

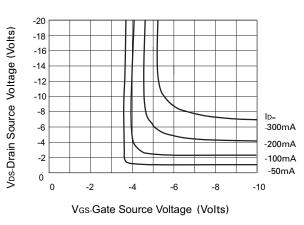
#### **Typical charateristics**

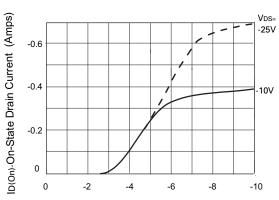


Vgs= -0.4 -10V -8V -7V -6V ID(On) -On-State Drain Current (Amps) -0.3 -5V -0.2 -4.5V -4V -3.5V -2 -6 -8 -10 -4 VDS - Drain Source Voltage (Volts)

#### **Output Characteristics**

**Saturation Characteristics** 

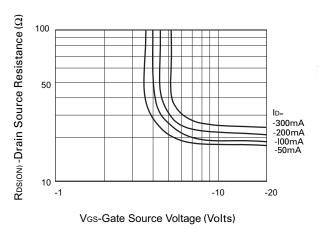


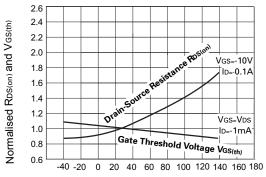


#### **Voltage Saturation Characteristics**

Vgs-Gate Source Voltage (Volts)

Transfer Characteristics



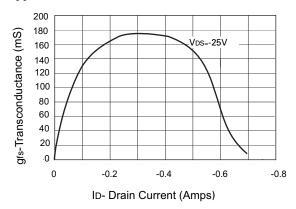


On-resistance vs gate-source voltage

T-Temperature (°C)

Normalised RDs(on) and Vgs(th) vs Temperature

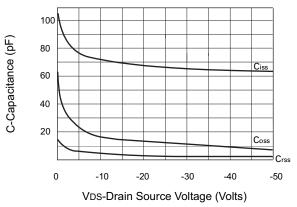
#### **Typical characteristics**

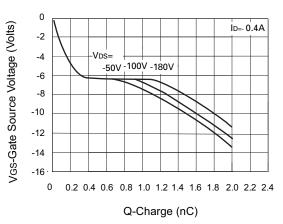


200 180 gfs-Transconductance (mS) 160 140 120 VDS=-25V 100 80 60 40 20 0 -2 -6 -10 VGS-Gate Source Voltage (Volts)

#### Transconductance v drain current

Transconductance v gate-source voltage

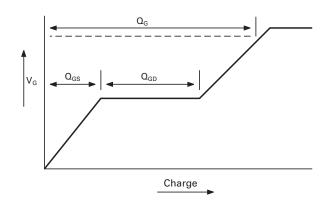




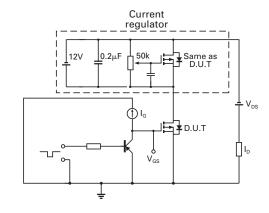
Capacitance v drain-source voltage

Gate charge v gate-source voltage

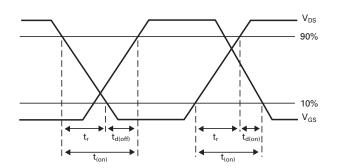
# **Typical characteristics**



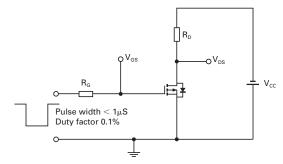
Basic gate charge waveform



Gate charge test circuit



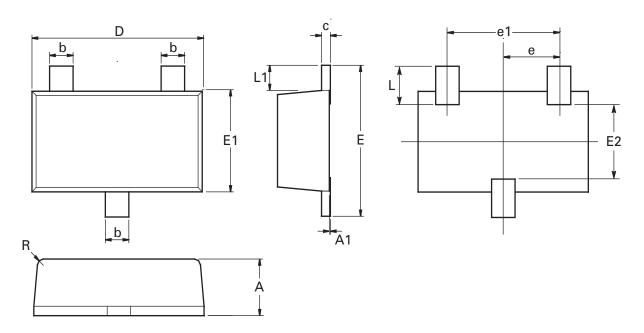
**Switching time waveforms** 



Switching time test circuit

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# Package outline - SOT23F



| Dim. | Millin | neters | Inc    | hes    | Dim. | Millim | eters | Inc    | hes    |
|------|--------|--------|--------|--------|------|--------|-------|--------|--------|
|      | Min.   | Max.   | Min.   | Max.   |      | Min.   | Max.  | Max.   | Max.   |
| Α    | 0.80   | 1.00   | 0.0315 | 0.0394 | Е    | 2.30   | 2.50  | 0.0906 | 0.0984 |
| A1   | 0.00   | 0.10   | 0.00   | 0.0043 | E1   | 1.50   | 1.70  | 0.0590 | 0.0669 |
| b    | 0.35   | 0.45   | 0.0153 | 0.0161 | E2   | 1.10   | 1.26  | 0.0433 | 0.0496 |
| С    | 0.10   | 0.20   | 0.0043 | 0.0079 | L    | 0.48   | 0.68  | 0.0189 | 0.0268 |
| D    | 2.80   | 3.00   | 0.1102 | 0.1181 | L1   | 0.30   | 0.50  | 0.0153 | 0.0161 |
| е    | 0.95   | ref    | 0.037  | 74 ref | R    | 0.05   | 0.15  | 0.0019 | 0.0059 |
| e1   | 1.80   | 2.00   | 0.0709 | 0.0787 | 0    | 0°     | 12°   | 0°     | 12°    |

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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| "Not recommended for new designs" | Device is still in production to support existing designs and production  |
| "Obsolete"                        | Production has been discontinued  |
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